

(19) World Intellectual Property
Organization
International Bureau



(43) International Publication Date
10 June 2004 (10.06.2004)

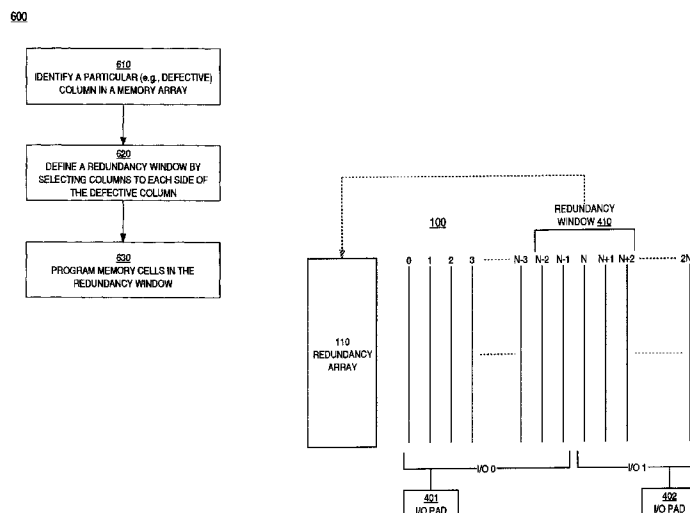
PCT

(10) International Publication Number
WO 2004/049350 A1

- (51) International Patent Classification⁷: **G11C 29/00**
- (21) International Application Number:
PCT/US2003/022003
- (22) International Filing Date: 10 July 2003 (10.07.2003)
- (25) Filing Language: English
- (26) Publication Language: English
- (30) Priority Data:
10/305,700 26 November 2002 (26.11.2002) US
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3453 (US).
- (81) Designated States (*national*): AE, AG, AL, AM, AT, AU,
AZ, BA, BB, BG, BR, BY, BZ, CA, CH, CN, CO, CR, CU,
CZ, DE, DK, DM, DZ, EC, EE, ES, FI, GB, GD, GE, GH,
GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC,
LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW,
MX, MZ, NO, NZ, OM, PH, PL, PT, RO, RU, SD, SE, SG,
SK, SL, TJ, TM, TR, TT, TZ, UA, UG, UZ, VN, YU, ZA,
ZM, ZW.
- (84) Designated States (*regional*): ARIPO patent (GH, GM,
KE, LS, MW, MZ, SD, SL, SZ, TZ, UG, ZM, ZW),
Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM),
European patent (AT, BE, BG, CH, CY, CZ, DE, DK, EE,
ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PT, RO,
SE, SI, SK, TR), OAPI patent (BF, BJ, CF, CG, CI, CM,
GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).
- Published:**
— with international search report

[Continued on next page]

(54) Title: METHOD AND SYSTEM FOR DEFINING A REDUNDANCY WINDOW AROUND A PARTICULAR COLUMN IN A MEMORY ARRAY



(57) Abstract: A method (600) of memory redundancy, and a system (100) thereof, are described. A memory array typically includes a plurality of columns (e.g., bit lines) of memory cells. A particular (e.g., defective) column of the memory array is identified (610). A redundancy window (410) is defined by selecting a group of adjacent columns including the defective column (620). The number of columns in the group of selected columns may be equal to the number of columns in a redundancy array (110) that is coupled to the memory array. The redundancy array is for storing information that would have been otherwise stored in the memory cells in the redundancy window. The group is selected such that there is at least one column on one side of the defective column and another column on the other side of the defective column. Typically, there will be multiple columns on each side of the defective column. The memory cells in these columns are programmed (630).

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